

REMARKS

Applicant amended claims 1, 7, 8, 9, 15, 16, 17, 19 and 20 for additional clarity.

Rejections Under Sections 102 and 103

Applicant incorporates by reference its remarks filed responsive to the Office Action of March 9, 2005, and the preliminary remarks filed September 23, 2005.

In addition, please consider the following. Neither '327 nor '991, either singly or in combination, teaches, discloses or suggests Applicant's invention.

In Tokumaru et al. ('327) reference (column 3 line 1 to 6), the socket apparatus is applied to test semiconductor devices having electrical leads protruding from the sides of the device (either two sides or four sides). Tokumaru et al. discloses "resistance...from 10^{10} to 10^{14} ohms." In Hornchek et al. (6,541,991) reference, the interface apparatus is applied to test ball grid array integrated devices which has solder balls on the back side of the device. In the present invention, the socket is applied to test semiconductor device which has leads such as pins, solder balls, solder pads, solder columns and the like on the back side of the device.

In Tokumaru et al. ('327) reference, metallic contactors 3 are arranged on the circumference of the bearer 2 to be brought into contact with the leads 12. (column 3 line 23-25). The resistance of the material used for making the bearer 2 is kept as low value as possible in a range that can sustain the isolating characteristics. (column 4 line 53-55).

The present invention discloses that the frame is made of conductive material which has a surface resistivity of approximately 10^6 Ohms/sq or less. Tokumaru et al. teaches 10^{10} to 10^{14} ohms (col. 4, lines 46-50), but does not teach "a surface resistivity of not greater than approximately 10^6 ohms/sq" or less as claimed by Applicant herein. If the bearer 2 in Tokumaru et al. ('327) reference were built out of a material which has a surface resistivity of 10^6 Ohms/sq or less, then metallic contactors 3 and the leads 12 of Tokumaru et al. would be all shorted by contacting with bearer 2, and the device of Tokumaru et al. would become non-functional for its intended purpose. Applicant respectfully submits that the last sentence in Item 3 of the Examiner's "Detailed Petition" is not correct. Tokumaru et al. fails to disclose a surface resistivity of not greater than 10^6 Ohms/sq as claimed by Applicant herein.

Entry and reconsideration are respectfully requested.

Respectfully Submitted,

Patrick J. Rafter et al.

By:

Joseph P. Abate 21-Feb-2006
Joseph P. Abate
Attorney for Applicant
Registration No. 30,238
Telephone No. 845-894-4633